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FORM PTO-1449 U.S. DEPARTMENT OF PATENT AND TRADE					1293.12	1293.1216C 10/82					
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	ATTORNEY DOCKET NO.	APPLICATION NO.
•	1293.1216C	10/828,298
LIST OF COPENDING APPLICATIONS	FIRST NAMED INVENTOR	
,	Sung-hee HWANG et	al.
	FILING DATE	GROUP ART UNIT
	April 21, 2004	

The following, prior-filed, copending U.S. patent application(s) is/are listed in accordance with the duty of disclosure provisions of 37 CFR § 1.56, so that the Examiner may consider same should he deem any thereof to be material to examination of the subject application. Pursuant to 37 CFR 1.98(a)(2)(iii), a copy of the identified copending application(s) is provided.

It is requested that the Examiner acknowledge his consideration of application(s) below-listed by initialling same in the space provided adjacent each such application and that the Examiner sign and date this form at the bottom thereof to confirm such consideration having been given.

This submission in no way represents an admission that any of the information listed herein constitutes prior art with respect to the subject application and unless and until such prior art status is established, this submission is not a request that the information presented herein be printed on the face of any patent issuing from the subject application in which this information is being filed.

**U.S. PATENT APPLICATION DOCUMENTS** 

*EXAMINER INIT/AL		U.S. SERIAL NO.	FILING DATE	NAME	ASSIGNEE
	1	10/124,366	April 18, 2002	Hwang et al.	Samsung Electronics Co., Ltd.
	2	10/828,297	April 21, 2004	Hwang et al.	Samsung Electronics Co., Ltd.
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Sheet 1 of 1 ATTORNEY DOCKET NO. U.S. DEPARTMENT OF COMMERCE **FORM PTO-1449** PATENT AND TRADEMARK OFFICE 10/828,298 1293.1216C FIRST NAMED INVENTOR LIST OF REFERENCES CITED BY APPLICANT Sung-hee HWANG et al. FILING DATE **GROUP ART UNIT** (Use several sheets if necessary) April 21, 2004 **U.S. PATENT DOCUMENTS** \*EXAMINER DOCUMENT SUB-FILING INITIAL NO. **CLASS CLASS** DATE DATE NAME AA 6,539,512 03/25/03 Jeong et al. AB AC AD AE AF FOREIGN PATENT DOCUMENTS **DOCUMENT** SUB-**TRANSLATION** NO. CLASS **CLASS** YES NO DATE COUNTRY AG AH ΑI AJ AK AL. OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.) Patent Abstract of Japan, Vol. 2000, No. 5, September 14, 2000 AN Japanese Patent Abstract 2000 057700, February 25, 2000 DATE CONSIDERED **EXAMINER** \*EXAMINER: /Initial if reference considered, whether or not citation is in conformance with MPEP 609: Draw line through citation if not in/conformance and not considered. Include copy of this form with next communication to applicant.

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